

NC-10 NON-CONTACT TYPE SHEET RESISTANCE/RESISTIVITY MEASUREMENT

NC-10



- Single Point, Non-Contact Type by Eddy Current method
- PC Controlled with software
- Temperature correction function for silicon wafer
- Sample Size:
 - ✓ Standard: 3" to 8" diameter, 156mm x 156mm
 - ✓ Optional: 2" or 12" diameter, 210mm x 210mm
- Measure Range depends on selected Probe Type

MEASURE RANGE				
PARAMETER	LOW PROBE TYPE	MIDDLE PROBE TYPE	HIGH PROBE TYPE	S-HIGH PROBE TYPE
RESISTIVITY (Ω .cm)	0.001 to 0.05	0.05 to 0.5	0.5 to 60.0	60.0 to 200.0
SHEET RESISTANCE (Ω /Sq)	0.01 to 0.5	0.5 to 10.0	10.0 to 1k	1k to 3k

APPLICABLE MATERIALS

- Semiconductor and Solar-cell materials (Silicon, Polysilicon, SiC etc)
- Functional materials (Carbon nanotube, DLC, graphene, Ag nanowire etc)
- Conductive thin film (Metal, ITO etc)
- Silicon-related epitaxial materials, Ion-implantation sample
- Chemical Compound Semiconductor (GaAs Epi, GaN Epi, InP, Ga etc)
- Others: On Request